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For Immediate Release

Akrometrix Announces Next Generation Thermal Warpage Measurement Tool the PS600T

Atlanta, Georgia - Akrometrix, LLC, the leading provider of Thermal Warpage and Strain Metrology Equipment for semiconductor and electronics industries, recently announced the next generation in thermal warpage metrology with its PS600T system. This system greatly improves temperature uniformity and heating rates, allowing for industry leading emulation of reflow conditions.

Featuring a multi-zone bottom heater and independently controlled topside heaters, the PS600T allows uniform heating and cooling, covering temperature ranges from room temperature to 300°C. The large format tool and heating system are designed around samples up to 600x600mm in size. The new tool offers new levels of automation in lensing, temperature response, and a new touch screen HMI, with foreign language support.

The PS600T is expandable to include Akrometrix modules for Digital Fringe Projection technology, to complement shadow moiré and cover different sample application needs, as well as Digital Image Correlation to measure surface strain and calculate composite CTE of materials.

For more information about Akrometrix's warpage metrology systems, including the PS600T currently available for sale, please contact them at equipmentsales@akrometrix.com or go to www.akrometrix.com.